# **ECOSPARK®** Ignition IGBT

300 mJ, 360 V, N-Channel Ignition IGBT

## ISL9V3036S3ST-F085C

#### **Features**

- SCIS Energy = 300 mJ at  $T_J = 25$ °C
- Logic Level Gate Drive
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **Applications**

- Automotive Ignition Coil Driver Circuits
- High Current Ignition System
- Coil on Plug Applications

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Parameter	Symbol	Value	Unit
Collector to Emitter Breakdown Voltage (I <sub>C</sub> = 1 mA)	BV <sub>CER</sub>	360	٧
Emitter to Collector Voltage – Reverse Battery Condition (I <sub>C</sub> = 10 mA)	BV <sub>ECS</sub>	24	٧
$I_{SCIS}$ = 14.2 A, L = 3.0 mHy, R <sub>GE</sub> = 1 k $\Omega$ , T <sub>C</sub> = 25°C (Note 1)	E <sub>SCIS25</sub>	300	mJ
$I_{SCIS}$ = 10.6 A, L = 3.0 mHy, R <sub>GE</sub> = 1 kΩ, T <sub>C</sub> = 150°C (Note 2)	E <sub>SCIS150</sub>	170	mJ
Collector Current Continuous, at V <sub>GE</sub> = 4.0 V, T <sub>C</sub> = 25°C	IC25	21	Α
Collector Current Continuous, at V <sub>GE</sub> = 4.0 V, T <sub>C</sub> = 110°C	IC110	17	Α
Gate to Emitter Voltage Continuous	$V_{GEM}$	±10	V
Power Dissipation Total, T <sub>C</sub> = 25°C	PD	150	W
Power Dissipation Derating, T <sub>C</sub> > 25°C	PD	1.10	W/°C
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>STG</sub>	-40 to 175	°C
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)	TL	300	°C
Reflow soldering according to JESD020C	T <sub>PKG</sub>	260	°C
HBM–Electrostatic Discharge Voltage at 100 pF, 1500 $\Omega$	ESD	4	kV
CDM-Electrostatic Discharge Voltage at 1 $\Omega$	ESD	2	kV

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Self Clamped inductive Switching Energy (ESCIS25) of 300 mJ is based on the test conditions that is starting T<sub>J</sub> = 25°C, L = 3.0 mHy, I<sub>SCIS</sub> = 14.2 A, V<sub>CC</sub> = 100 V during inductor charging and V<sub>CC</sub> = 0 V during time in clamp.
- V<sub>CC</sub> = 100 V during inductor charging and V<sub>CC</sub> = 0 V during time in clamp.

  2. Self Clamped inductive Switching Energy (ESCIS150) of 170 mJ is based on the test conditions that is starting T<sub>J</sub> = 150°C, L = 3.0 mHy, I<sub>SCIS</sub> = 10.6 A, V<sub>CC</sub> = 100 V during inductor charging and V<sub>CC</sub> = 0 V during time in clamp.



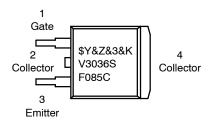
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D<sup>2</sup>PAK-3 CASE 418AJ

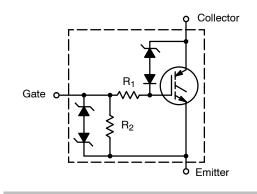
#### **MARKING DIAGRAM**



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Date Code (Week & Year)

&K = Lot Code

V3036SF085C = Specific Device Code



#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

## THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Case - Steady State (Drain)	$R_{ heta JC}$	1.0	°C/W

#### **ELECTRICAL CHARACTERISTICS** (T<sub>.I</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•	•		•		•	•
Collector to Emitter Breakdown Voltage	BV <sub>CER</sub>	$I_{CE}$ = 2 mA, $V_{GE}$ = 0 V, $R_{GE}$ = 1 k $\Omega$ , $T_{J}$ = -40 to 150°C		330	360	390	V
Collector to Emitter Breakdown Voltage	BV <sub>CES</sub>	$I_{CE}$ = 10 mA, $V_{GE}$ = 0 V, $R_{GE}$ = 0 $\Omega$ , $T_{J}$ = -40 to 150°C		350	380	410	٧
Emitter to Collector Breakdown Voltage	BV <sub>ECS</sub>	$I_{CE} = -75 \text{ mA}, V_{GE} = 0 \text{ V}, T_{J} = 25^{\circ}\text{C}$		30	_	_	٧
Gate to Emitter Breakdown Voltage	BV <sub>GES</sub>	$I_{GES} = \pm 2 \text{ mA}$		±12	±14	_	V
Collector to Emitter Leakage	I <sub>CER</sub>	$V_{CE}$ = 175 V, $R_{GE}$ = 1 k $\Omega$	T <sub>J</sub> = 25°C	-	-	25	μΑ
Current			T <sub>J</sub> = 150°C	1 -	-	1	mA
Emitter to Collector Leakage	I <sub>ECS</sub>	V <sub>EC</sub> = 24 V	T <sub>J</sub> = 25°C	1 -	-	1	mA
Current			T <sub>J</sub> = 150°C	1 -	-	40	1
Series Gate Resistance	R <sub>1</sub>	<u>'</u>		<b>1</b> -	70	-	Ω
Gate to Emitter Resistance	R <sub>2</sub>			10	-	26	kΩ
ON CHARACTERISTICS							
Collector to Emitter Saturation	V <sub>CE(SAT)</sub>	$I_{CE} = 6 \text{ A}, V_{GE} = 4.0 \text{ V}, T_{J} = 25^{\circ}\text{C}$ $I_{CE} = 10 \text{ A}, V_{GE} = 4.5 \text{ V}, T_{J} = 150^{\circ}\text{C}$ $I_{CE} = 15 \text{ A}, V_{GE} = 4.5 \text{ V}, T_{J} = 150^{\circ}\text{C}$		-	1.25	1.60	V
Voltage				-	1.58	1.80	V
				-	1.90	2.20	V
DYNAMIC CHARACTERISTICS							
Gate Charge	Q <sub>G(ON)</sub>	I <sub>CE</sub> = 10 A, V <sub>CE</sub> = 12 V, V <sub>GE</sub> = 5 V		-	17	_	nC
Gate to Emitter Threshold	V <sub>GE(TH)</sub>	I <sub>CE</sub> = 1 mA, V <sub>CE</sub> = V <sub>GE</sub>	T <sub>J</sub> = 25°C	1.3	-	2.2	V
Voltage			T <sub>J</sub> = 150°C	0.75	-	1.8	
Gate to Emitter Plateau Voltage	$V_{GEP}$	V <sub>CE</sub> = 12 V, I <sub>CE</sub> = 12 A		-	3.0	-	V
SWITCHING CHARACTERISTIC	cs						
Current Turn-On Delay Time-Resistive	td <sub>(ON)R</sub>	$\begin{aligned} &V_{CE} = 14 \text{ V, } R_L = 1  \Omega, V_{GE} = 5 \text{ V, } R_G = 1 \text{ k} \Omega, \\ &T_J = 25^{\circ}\text{C} \end{aligned}$		_	0.7	4	μs
Current Rise Time-Resistive	t <sub>rR</sub>			-	2.1	7	1
Current Turn-Off Delay Time-Inductive	td <sub>(OFF)L</sub>	$V_{CE}$ = 300 V, L = 500 μH, $V_{GE}$ = 5 V, $R_{G}$ = 1 kΩ, $T_{J}$ = 25°C		-	4.8	15	1
Current Fall Time-Inductive	t <sub>fL</sub>	1		_	2.8	15	1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
ISL9V3036S3ST-F085C	D <sup>2</sup> PAK-3 (Pb-Free)	800 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **TYPICAL CHARACTERISTICS**

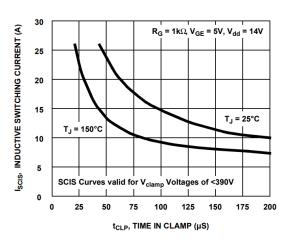


Figure 1. Self Clamped Inductive Switching Current vs. Time in Clamp

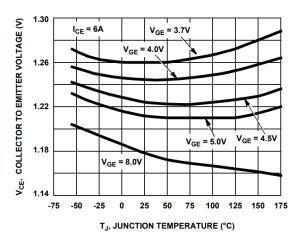


Figure 3. Collector to Emitter On–State Voltage vs. Junction Temperature

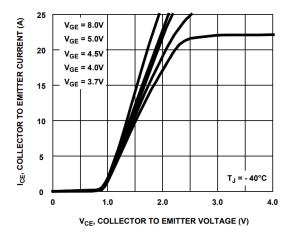


Figure 5. Collector to Emitter On-State Voltage vs. Collector Current

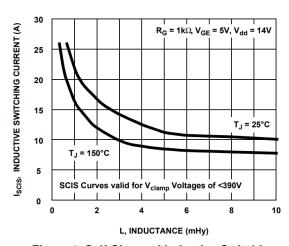


Figure 2. Self Clamped Inductive Switching Current vs. Inductance

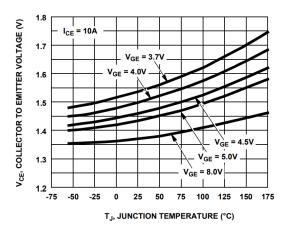


Figure 4. Collector to Emitter On-State Voltage vs. Junction Temperature

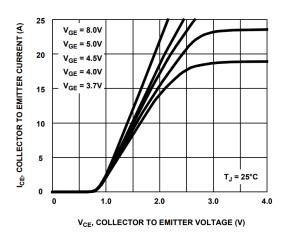


Figure 6. Collector to Emitter On- State Voltage vs. Collector Current

## TYPICAL CHARACTERISTICS (Continued)

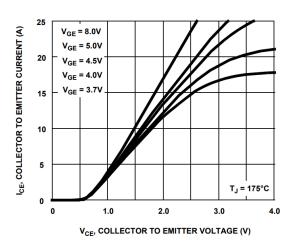


Figure 7. Collector to Emitter On-State Voltage vs. Collector Current

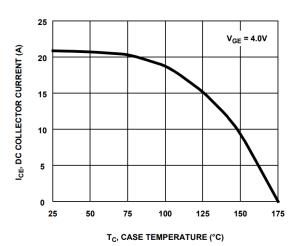


Figure 9. DC Collector Current vs. Case Temperature

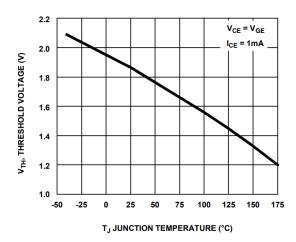


Figure 11. Threshold Voltage vs. Junction Temperature

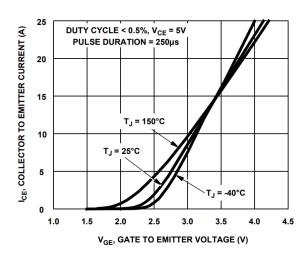


Figure 8. Transfer Characteristics

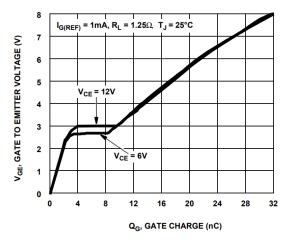


Figure 10. Gate Charge

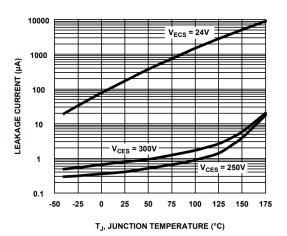
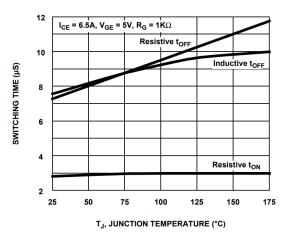


Figure 12. Leakage Current vs. Junction Temperature

## TYPICAL CHARACTERISTICS (Continued)



1600 FREQUENCY = 1 MHz

1200 C<sub>IES</sub>

0 5 10 15 20 25

V<sub>CE</sub>, COLLECTOR TO EMITTER VOLTAGE (V)

Figure 13. Switching Time vs. Junction Temperature

Figure 14. Capacitance vs. Collector to Emitter Voltage

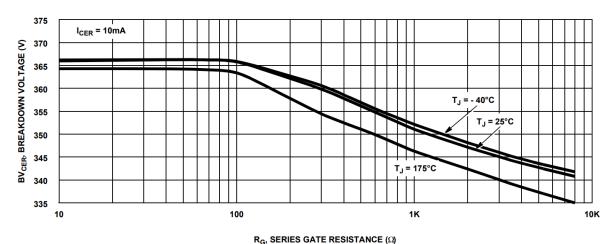


Figure 15. Break down Voltage vs. Series Resistance

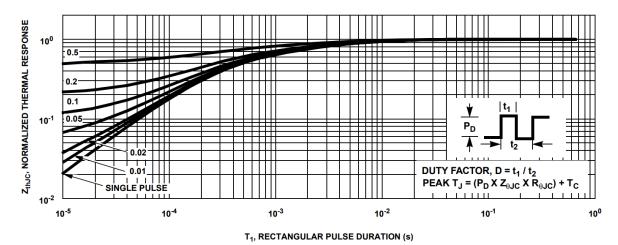


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

## **TEST CIRCUIT AND WAVEFORMS**

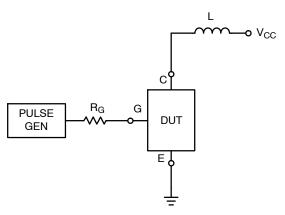


Figure 17. Inductive Switching Test Circuit

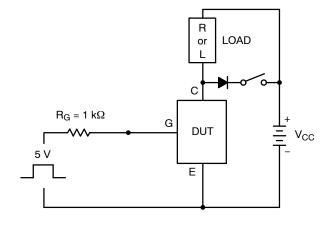


Figure 18.  $t_{\text{ON}}$  and  $t_{\text{OFF}}$  Switching Test Circuit

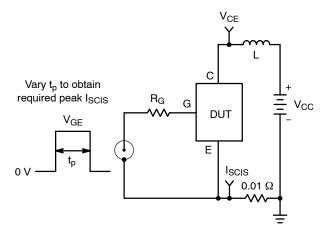


Figure 19. Energy Test Circuit

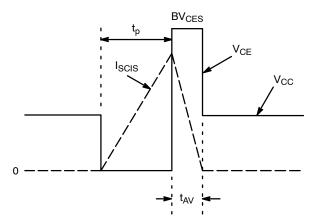


Figure 20. Energy Waveforms

#### PACKAGE DIMENSIONS

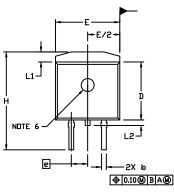
## D<sup>2</sup>PAK-3 (TO-263, 3-LEAD) CASE 418AJ

**ISSUE E** 

#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: INCHES
- CHAMFER OPTIONAL.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE DUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1, AND E1.
- OPTIONAL MOLD FEATURE
- 7. ①,② ... OPTIONAL CONSTRUCTION FEATURE CALL DUTS.

	INCHES		MILLIN	ETERS
DIM	MIN.	MAX.	MIN.	MAX.
Α	0.160	0.190	4.06	4.83
A1	0.000	0.010	0.00	0.25
b	0.020	0.039	0.51	0.99
С	0.012	0.029	0.30	0.74
c2	0.045	0.065	1.14	1.65
D	0.330	0.380	8.38	9.65
D1	0.260		6.60	i
E	0.380	0.420	9.65	10.67
E1	0.245		6.22	-
e	0.100	BSC	2.54 BSC	
Н	0.575	0.625	14.60	15.88
L	0.070	0.110	1.78	2.79
L1		0.066		1.68
L2		0.070		1.78
L3	0.010 BSC		0.25 BSC	
М	-8*	8*	-8*	8*



RECOMMENDED MOUNTING FOOTPRINT

0.436

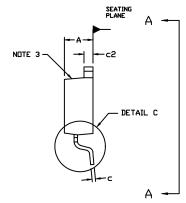
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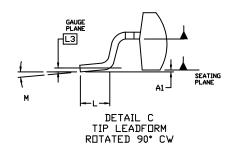
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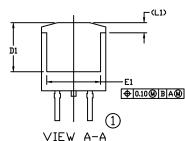
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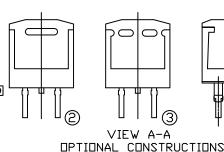
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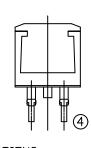
0.100 PITCH











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